

**Search Notes**

Application/Control No.

10/657,445

Examiner

James D. Stein

Applicant(s)/Patent under  
Reexamination

GRAU ET AL.

Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
359	5,174-177	6/9/2005	JDS
398	33	6/9/2005	JDS
702	66	6/9/2005	

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
files	removed	6/9/2005	JDS

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
see attached EAST search history	6/9/2005	JDS
IEEE and INSPEC: eye diagram, probability, threshold, counter, adder, subtract, sampling	6/9/2005	JDS